ADC ANALYSIS AND AGING, BCM1F



BRM Meeting

Zeuthen



Brandenburgische Technische Universität







- > Baseline Definition
- > Signal Amplitude Spectra
- > Baseline Measurements 2011
- > Time Arriving Fill Structure (ADC & TDC)
- > BCM1F Time Resolution
- > Radiation Aging
- Long Signals
- > Conclusions



Introduction



- > 8 sCVD diamond sensors of BCM1F deliver bunch-by-bunch information on both the beam halo and collision products near the beam pipe and close to the IP in CMS.
- Modules (sensor, a pre-amplifier and an optical driver) at 4.5 cm from the beam axis, Z position - 1.8 m on both sides of the IP.
- > Allow to measure the flux of beam halo particles as well as of collision products.



Baseline Calculation



Amplitude Spectrum



Baseline stability is important for amplitude calculations Red – 100 BL averaging

Length of signal over threshold as a function of signal amplitude. >Blue – single baseline determination > Most of long signals are in saturation

>Low threshold 0.1 ADC counts leads to >Improves pedestal & saturation peak overlapping of signals and shows double and triple peaks



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Signal Amplitude vs. Signal Length





By setting fixed threshold arriving time distribution has a jitter
 Constant Fraction Discrimination – CFD Time over threshold ~40ns for 50% of amplitude.



Baseline Tool



Full 2011 baseline tool for BCM1F was operated

BL Tool is sensitive for temperature and collisions

BL moved down in ~10ADC counts

Low values are corresponding switched off HV and LV

DESY



Bunch structure repetition as in TDC



Finding of ADC signals with fixed threshold



Bunch structure repetition as in TDC



Time Resolution by BCM1F ADC module



- > Time Resolution Measurements with test pulses:
- > TP feed to FE-electronics of all modules and measured by ADC
- > Trigger for ADC can be TP or orbit clock
- For Intrinsic Time Resolution with TP, one TP is plugged to ADC directly



Time Resolution with Test Pulses

Arriving Time Distribution – in respect to ADC trigger (Test pulses were feed to ADC trigger in and 1ADC channel) Intrinsic Time Resolution – two ADC channels in respect to each other (Test pulses were feed to 2ADC channels)

Jitter due to ADC trigger chock – can be up to 16 ns



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LHC Operating Stages by BCM1F



- > Hit rate with the scalers during an LHC fill. Different steps of the fill are well characterized.
- Flat top stage after injection and acceleration and before squeezing (collisions) → No collision products.
- Flat top operating step was used for measuring halo particles by ADC.



Intrinsic Time Resolution, CFD FlatTop measurements



Over several Fills at Flat Top stage ADC data was recorded Coincidence of two signals in two ADC channels are taken Time over threshold is calculated as 50% of amplitude with CFD method Difference between cannel ~12 ns Sigma = 2.18±0.16, ITR = $\sigma/\sqrt{2}$ = 1,54 ns Previous result was 1,8 ns (Ringo Schmidt 2009)



Test Pulses Monitoring



>Over 2011 test pulses measurements were done regularly to monitor FEelectronics degradation

Dependence of test pulses amplitude in respect to baseline shown as a function of integrated luminosity. -1 point shows values of test pulses amplitudes measured in 2009.



Aging



- > Take spectra over half year (May, October, November)
- Shift in Saturation peak in 12%
- > MIP peak shift depend on fitting 10-20%



Time Over Threshold & Undershoot Time



Proton Fill 2261
TDC thresholds to calculate time over threshold
For undershoot – BL – MIP signals
14 files over one fill were measured with ADC
First undershoot time and TOT were correlated with collision rates from LHC



Conclusions

- > ADC is a perfect tool for BCM1F characterization
- > Allows to see Amplitude Spectra (MIP peaks, Saturation peaks, Separation between noise and signals)
- > Baseline stability is important
- Repeats time arriving distribution as by TDC
- > Arriving time distribution ~ 6 ns
- Intrinsic Time Resolution ~ 1,5 ns
- > Aging in FE electronics is observed and will be defined better for new BL method
- Time when BCM1F is not recording signals correlates to collision rates



Thank You!



HV scan for BCM1F







- HV scan was made in
 May and November
 2011
- > BL stability affect MIP definition
- Problems with Landau fitting at low voltages
- In saturation for most of modules after 200V

